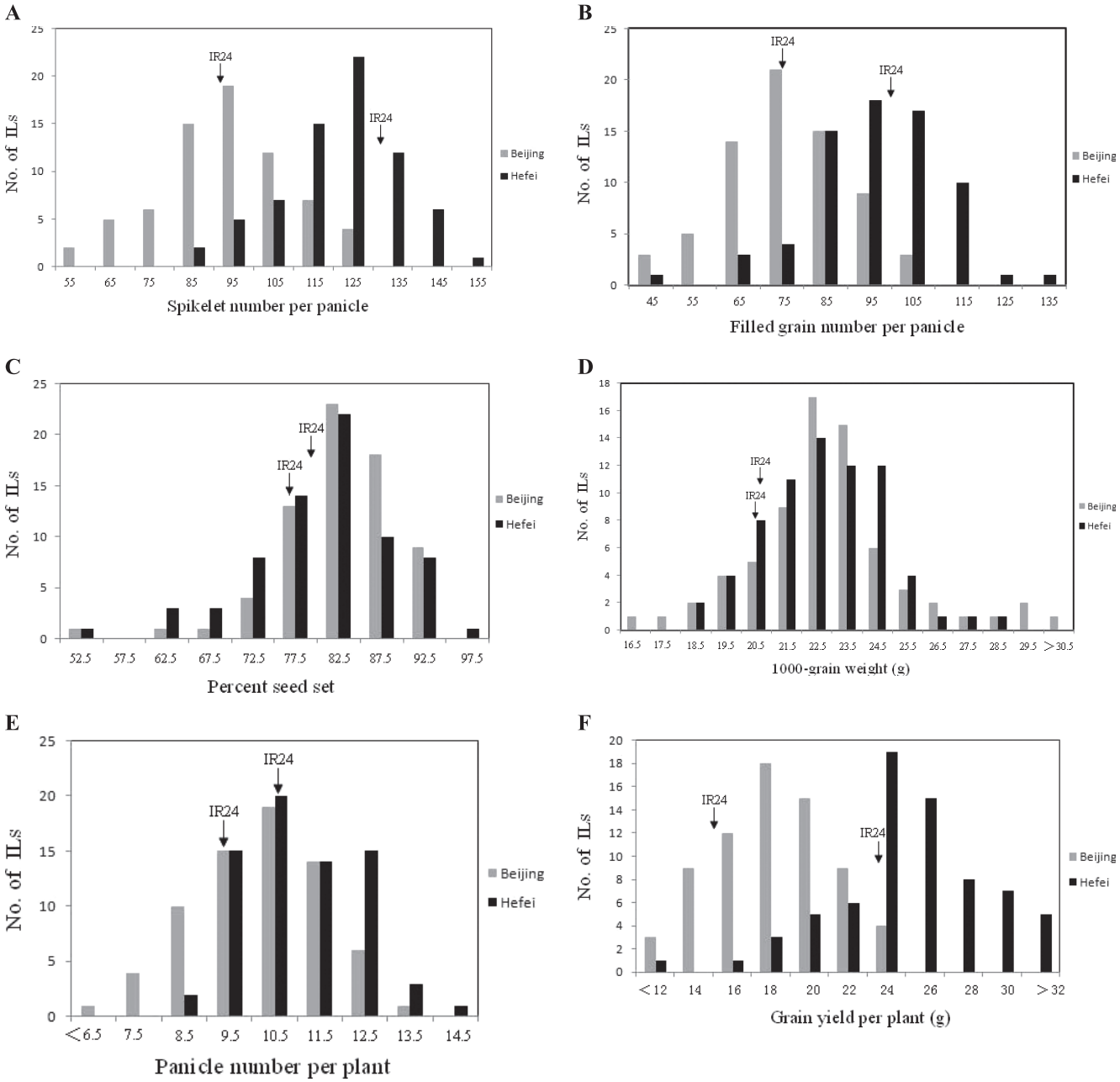
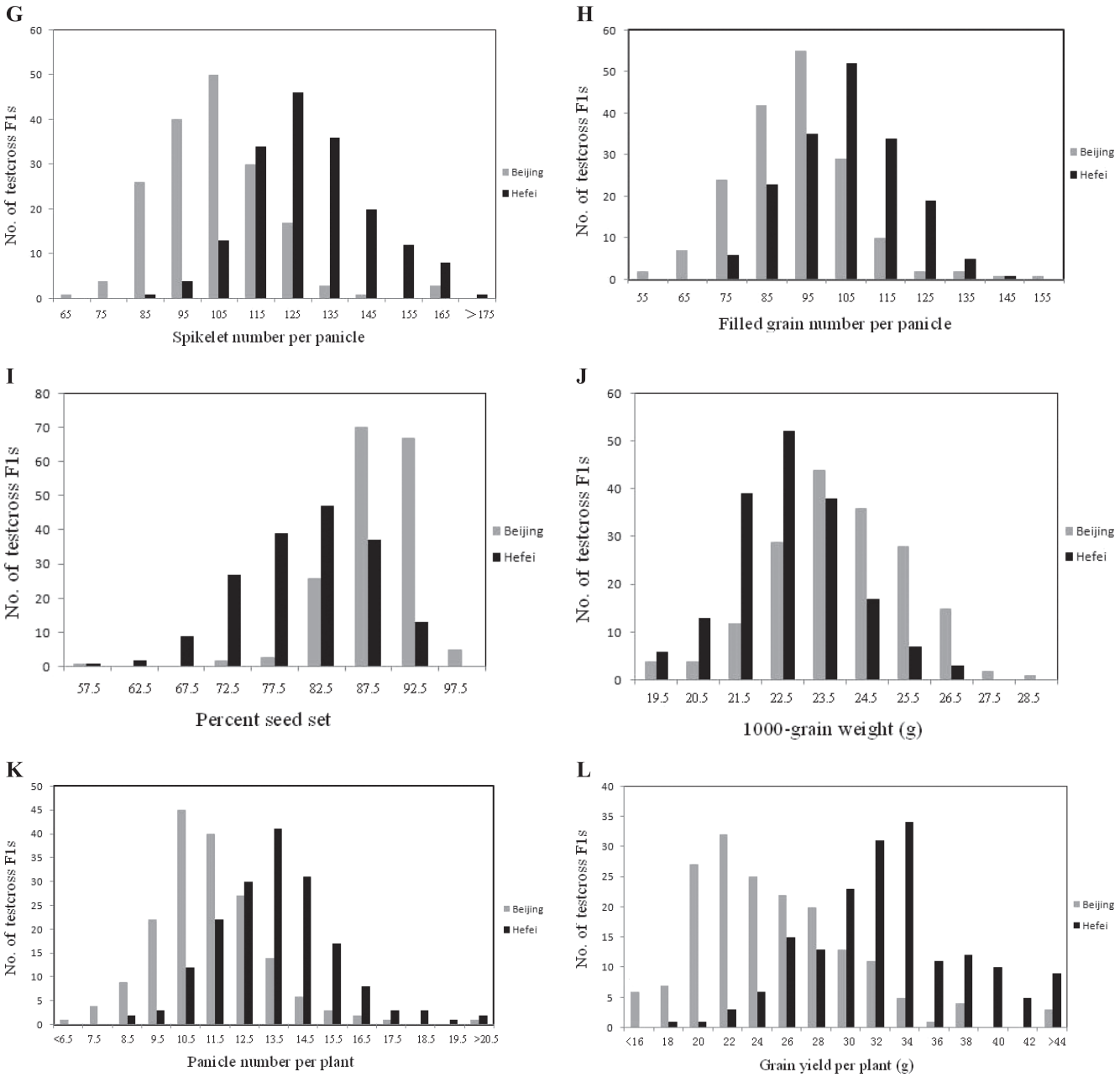


Supplemental Fig. 1. Frequency distribution of six yield-related traits for ILs and testcross F_1s. ILs were generated from a cross between IR24, a *indica* cultivar, as the recurrent parent, and Asominori, a typical *japonica* cultivar, as the donor parent. Testcross F_1s derived from the cross between ILs. (A) Frequency distribution of spikelet number per plant in ILs; (B) Frequency distribution of filled grain number per plant in ILs; (C) Frequency distribution of percent seed set in ILs; (D) Frequency distribution of 1000-grain weight in ILs; (E) Frequency distribution of panicle number per plant in ILs; (F) Frequency distribution of grain yield per plant in ILs; (G) Frequency distribution of spikelet number per plant in testcross F_1s; (H) Frequency distribution of filled grain number per plant in testcross F_1s; (I) Frequency distribution of percent seed set in testcross F_1s; (J) Frequency distribution of 1000-grain weight in testcross F_1s; (K) Frequency distribution of panicle number per plant in testcross F_1s; (L) Frequency distribution of grain yield per plant in testcross F_1s.



Supplemental Fig. 1. (continued)